

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/708,559	ONG, PUN CHOON
	<b>Examiner</b> Bena Miller	<b>Art Unit</b> 3725

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner